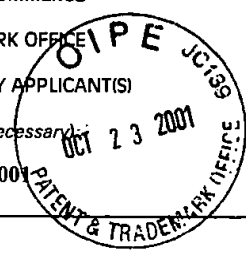
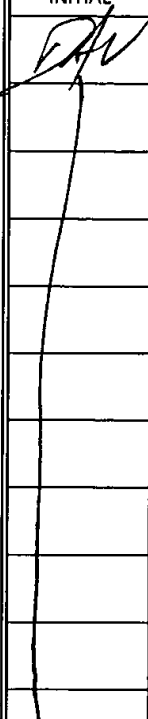
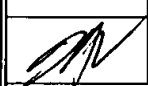
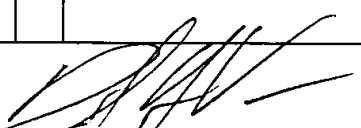
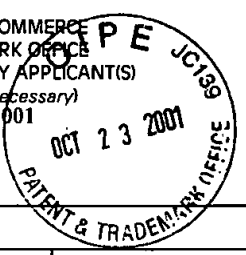
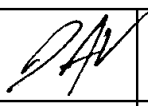

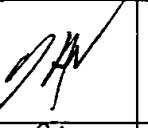


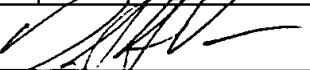


FORM PTO 1449 (modified)  U.S. DEPARTMENT OF COMMERCE  PATENT AND TRADEMARK OFFICE  LIST OF REFERENCES CITED BY APPLICANT(S) <i>(Use several sheets if necessary)</i>  Date Submitted to PTO: October 23, 2001			ATTY DOCKET NO. <b>862.C2170</b>		APPLICATION NO. <b>09/819,907</b>	
<div style="text-align: center;">  </div>			APPLICANT <b>Haruhiro ONO, et al.</b>			
			FILING DATE <b>March 29, 2001</b>		GROUP <b>2879</b>	
U.S. PATENT DOCUMENTS						
*EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
	5,834,783	11/10/1998	Muraki, et al.	250	398	
	5,864,142	01/26/1999	Muraki, et al.	250	491.1	
	5,905,267	05/18/1999	Muraki	250	492.22	
	5,981,954	11/09/1999	Muraki	250	397	
	6,107,636	08/22/2000	Muraki	250	492.2	
	6,104,035	08/15/2000	Muraki	250	492.22	
	6,166,387	12/26/2000	Muraki, et al.	250	492.2	
	5,929,454	07/27/1999	Muraki, et al.	250	491.1	
	5,939,725	08/17/1999	Muraki	250	492.22	
	5,973,332	10/26/1999	Muraki, et al.	250	492.2	
	6,137,113	10/24/2000	Muraki	250	492.22	
	4,419,580	12/06/1983	Walker, et al.	250	396 R	
FOREIGN PATENT DOCUMENTS						
	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES/NO/ OR ABSTRACT
OTHER DOCUMENT(S) (Including Author, Title, Date, Pertinent Pages, Etc.)						
EXAMINER			DATE CONSIDERED			
			<b>7/30/03</b>			

\*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered.

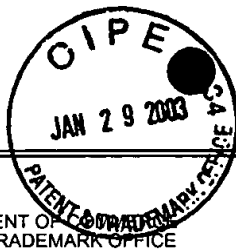
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Sheet 1 of 2

FORM PTO 1449 (modified) U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE LIST OF REFERENCES CITED BY APPLICANT(S) (Use several sheets if necessary) Date Submitted to PTO: <b>October 23, 2001</b>		ATTY DOCKET NO. <b>862.C2170</b>	APPLICATION NO. <b>09/819,907</b>			
<div style="text-align: center;">  </div>		APPLICANT <b>Haruhiro ONO, et al.</b>				
FILING DATE <b>March 29, 2001</b>		GROUP <b>2879</b>				
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	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES/NO/ OR ABSTRACT
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	"Sub-Nanometer Miniature Electron Microscope", A.D. Feinerman, et al., Journal of Vacuum Science and Technology A, Vol. 10, No. 4, July/August 1992, 611-616.					
	"High Aspect Ratio Aligned Multilayer Microstructure Fabrication", K. Y. Lee, et al., Journal of Vacuum Science and Technology B, Vol. 12, No. 6, November/December 1994, pp. 3425-3430.					
	"Arrayed Miniature Electron Beam Columns For High Throughput Sub-100 nm Lithography", T. H. P. Chang, et al., Journal of Vacuum Science and Technology B, Vol. 10, No. 6, November/December 1992, pp. 2743-2748.					
	"Microstructures for Particle Beam Control", G. W. Jones, et al., Journal of Vacuum Science and Technology B, Vol. 6, No. 6, November/December 1988, pp. 2023-2027.					
	"A Multibeam Scheme for Electron-Beam Lithography", T. Sasaki, Journal of Vacuum Science and Technology, Vol. 19, No. 4, November/December 1981, pp. 963-965.					
EXAMINER				DATE CONSIDERED <b>7/30/03</b>		

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Sheet 2 of 2



FORM PTO 1449 (modified)		ATTY DOCKET NO. 00862.022170		APPLICATION NO. 09/819,907		
U.S. DEPARTMENT OF PATENT AND TRADEMARK OFFICE		APPLICANT Haruhiro ONO et al.				
LIST OF REFERENCES CITED BY APPLICANT(S) (Use several sheets if necessary)		FILING DATE March 29, 2001		GROUP 2879		
January 29, 2003						
U.S. PATENT DOCUMENTS						
*EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
MA	5,121,234	06/09/1992	Kucera	359	50	
	5,604,394	02/18/1997	Saito et al.	313	422	
	6,381,702	04/30/2002	Ogasawara	713	500	
MA	2002/0051111	05/02/2002	Greene et al.	349	149	
FOREIGN PATENT DOCUMENTS						
	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES/NO/ OR ABSTRACT
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EXAMINER			DATE CONSIDERED			
MA			7/3/03			

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		APPLICANT Haruhiro ONO et al.					
		FILING DATE March 29, 2001			GROUP 2879		
U.S. PATENT DOCUMENTS							
*EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
DA		5,121,234	06/09/1992	Kucera	359	50	
		5,604,394	02/18/1997	Saito et al.	313	422	
		6,381,072	04/30/2002	Ogasawara	713	500	
DA		2002/0051111	05/02/2002	Greene et al.	349	149	
FOREIGN PATENT DOCUMENTS							
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EXAMINER		DATE CONSIDERED					
		7/30/03					

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